## Memory FRAM <br> CMOS

## 256 K (32 K $\times 8$ ) Bit

## MB85R256

## - DESCRIPTIONS

The MB85R256 is an FRAM (Ferroelectric Random Access Memory) chip in a configuration of 32,768 words $x$ 8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells.

Unlike SRAM MB85R256 is able to retain data without back-up battery.
The memory cells used for the MB85R256 has inproved at least $10^{10}$ times of read/write access per bit, significantly outperforming FLASH memory and EEPROM in durability.
The MB85R256 uses a pseudo - SRAM interface compatible with conventional asynchronous SRAM.

## ■ FEATURES

- Bit configuration: 32,768 words x 8 bits
- Read/write durability: $10^{10}$ times/bit (Min)
- Peripheral circuit CMOS construction
- Operating power supply voltage: 3.0 V to 3.6 V
- Operating temperature range: $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$
- 28-pin, SOP flat package
- 28-pin, $\operatorname{TSOP}(1)$ flat package


## PACKAGES

28-pin plastic SOP
(FPT-28P-M17)
(FPT-28P-M03)

## MB85R256

## PIN ASSIGNMENTS

(TOP VIEW)

(FPT-28P-M17)

(FPT-28P-M03)

## PIN DESCRIPTIONS

| Pin name | Function |
| :---: | :--- |
| $\mathrm{A}_{0}$ to $\mathrm{A}_{14}$ | Address Input |
| $\mathrm{I} / \mathrm{O}_{0}$ to $\mathrm{I} / \mathrm{O}_{7}$ | Data input/output |
| $\overline{\mathrm{CE}}$ | Chip enable input |
| $\overline{\mathrm{WE}}$ | Write Enable input |
| $\overline{\mathrm{OE}}$ | Output enable input |
| $\mathrm{V}_{\mathrm{cc}}$ | Power supply $(+3.3 \mathrm{~V} \mathrm{Typ})$ |
| GND | Ground |

## BLOCK DIAGRAM



## FUNCTION LIST

| Operation mode | $\overline{C E}$ | $\overline{\text { WE }}$ | $\overline{\text { OE }}$ | $\mathrm{I} / \mathrm{O}_{7}$ to I/O000 | Power supply current |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Standby precharge | H | $\times$ | $\times$ | High-Z | Standby (Iss) |
|  | $\times$ | L | L |  |  |
| Latch address | L | を | ₹ | - | - |
| Write | L | L | H | Data input | Operation (Icc) |
| Read | L | H | L | Data output |  |
| Output Disable | $\times$ | H | H | High-Z |  |

H : High level, L: Low level, x : Irrespective of " H " or " L "

## ABSOLUTE MAXIMUM RANGES

| Parameter |  | Symbol | Rating |  |
| :--- | :---: | :---: | :---: | :---: |
|  |  |  |  |
|  |  |  | Min | Max |  |
| Power supply voltage | $\mathrm{V}_{\mathrm{cc}}$ | -0.5 | +4.6 | V |
| Input voltage | $\mathrm{V}_{\mathrm{IN}}$ | -0.5 | $\mathrm{~V}_{\mathrm{cc}}+0.5$ | V |
| Output voltage | $\mathrm{V}_{\text {out }}$ | -0.5 | $\mathrm{~V}_{\mathrm{cc}}+0.5$ | V |
| Operating temperature | $\mathrm{T}_{\mathrm{A}}$ | -40 | +85 | ${ }^{\circ} \mathrm{C}$ |
| Storage temperature | Tstg | -40 | +85 | ${ }^{\circ} \mathrm{C}$ |

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

## ■ RECOMMENDED OPERATING CONDITIONS

| Parameter | Symbol | Value |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max |  |
| Power supply voltage | Vcc | 3.0 | 3.3 | 3.6 | V |
| High level input voltage | $\mathrm{V}_{\mathrm{H}}$ | $0.8 \times \mathrm{Vcc}$ | - | $\mathrm{V} \mathrm{cc}+0.5$ | V |
| Low level input voltage | VIL | -0.5 | - | + 0.6 | V |
| Operating temperature | TA | -40 | - | + 85 | ${ }^{\circ} \mathrm{C}$ |

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.
Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure.
No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

## - ELECTRICAL CHARACTERISTICS

## 1. DC Characteristics

(within recommended operating conditions)

| Parameter | Symbol | Conditions | Value |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Typ | Max |  |
| Input leakage current | \| إ1 | | $\mathrm{V}_{\mathrm{in}}=0 \mathrm{~V}$ to $\mathrm{V}_{\text {cc }}$ | - | - | 10 | $\mu \mathrm{A}$ |
| Output leakage current | \| lıo | | $\begin{aligned} & \mathrm{V} \text { out }=0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{cc}}, \\ & \overline{\mathrm{CE}}=\mathrm{V}_{I H} \text { or } \overline{\mathrm{OE}}=\mathrm{V}_{\mathrm{H}} \end{aligned}$ | - | - | 10 | $\mu \mathrm{A}$ |
| Operating power supply current | Icc | ```CE}=0.2 V Other Inputs = Vcc - 0.2 V/0.2 V, trc (Min), li/o = 0 mA``` | - | 5 | 10 | mA |
| Standby current | IsB | $\overline{\mathrm{CE}} \geq \mathrm{V}$ cc | - | 5 | 100 | $\mu \mathrm{A}$ |
| High level output voltage | Vон | $\mathrm{IoH}=-100 \mu \mathrm{~A}$ | $0.8 \times \mathrm{Vcc}$ | - | - | V |
| Low level output voltage | VoL | $\mathrm{loL}=1.0 \mathrm{~mA}$ | - | - | 0.4 | V |

2. AC Characteristics
(1) Read cycle
(within recommended operating conditions)

| Parameter | Symbol | Value |  | Unit |
| :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Max |  |
| Read cycle time | trc | 235 | - | ns |
| $\overline{\overline{C E}}$ active time | tca | 150 | 10,000 |  |
| Read pulse width | trp | 150 | 10,000 |  |
| Precharge time | tpc | 85 | - |  |
| Address setup time | $\mathrm{tas}^{\text {a }}$ | 0 | - |  |
| Address hold time | tah | 25 | - |  |
| $\overline{\mathrm{CE}}$ access time | tce | - | 150 |  |
| $\overline{\mathrm{OE}}$ access time | toe | - | 150 |  |
| $\overline{\mathrm{CE}}$ output floating time | thz | - | 25 |  |
| $\overline{\text { OE }}$ output floating time | tohz | - | 25 |  |

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## (2) Write cycle

(within recommended operating conditions)

| Parameter | Symbol | Value |  | Unit |
| :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Max |  |
| Write cycle time | twc | 235 | - | ns |
| $\overline{\text { CE }}$ active time | tcA | 150 | 10,000 |  |
| Write pulse width | twp | 150 | 10,000 |  |
| Precharge time | tpc | 85 | - |  |
| Address setup time | $\mathrm{tas}^{\text {a }}$ | 0 | - |  |
| Address hold time | taH | 25 | - |  |
| Data setup time | tos | 50 | - |  |
| Data hold time | toh | 0 | - |  |
| Write set up time | tws | 0 | - |  |
| Write hold time | twh | 0 | - |  |

## (3) Power ON/OFF sequence

(within recommended operating conditions)

| Parameter | Symbol | Value |  |  | Unit |
| :--- | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max |  |
| $\overline{\text { CE LEVEL hold time at power OFF }}$ | tpd | 85 | - |  | ns |
| $\overline{\text { CE LEVEL hold time at power ON }}$ | tpu | 85 | - | - | ns |
| Power interval | tpi | 1 | - | - | $\mu \mathrm{s}$ |

## 3. Pin Capacitance

| Parameter | Symbol | Conditions | Value |  |  | Unit |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Typ | Max |  |
| Input capacitance | $\mathrm{C} I \mathbb{N}$ | $\mathrm{~V}_{\mathbb{N}}=\mathrm{V}_{\text {out }}=\mathrm{GND}$, |  |  |  |  |
| output capacitance | Cout | $\mathrm{f}=1 \mathrm{MHz}, \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ | - | - | 10 | pF |
|  |  | - | - | 10 | pF |  |

## 4. AC Characteristics Test Condition

Power supply voltage $: 3.0 \mathrm{~V}$ to 3.6 V
Input voltage amplitude : 0.3 V to 2.7 V
Input rising time $: 10 \mathrm{~ns}$
Input falling time : 10 ns
Input evaluation level : $2.0 \mathrm{~V} / 0.8 \mathrm{~V}$
Output evaluation level : $2.0 \mathrm{~V} / 0.8 \mathrm{~V}$
Output load : 100 pF

## TIMING DIAGRAM

1. Read cycle ( $\overline{\mathrm{CE}}$ Control)

2. Read cycle ( $\overline{\mathrm{OE}}$ Control)


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## 3. Write cycle (CE Control)


4. Write cycle (WE Control)


## POWER ON/OFF SEQUENCE


*: $\overline{\mathrm{CE}}(\mathrm{Max})<\mathrm{V}_{\mathrm{cc}}+0.5 \mathrm{~V}$

## - NOTES ON USE

After IR reflow, the hold of data that was written before IR reflow is not guaranteed.

■ ORDERING INFORMATION

| Part number | Package | Remarks |
| :--- | :---: | :---: |
| MB85R256PF | 28-pin, plastic SOP <br> (FPT-28P-M17) |  |
| MB85R256PFTN | 28-pin, plastic TSOP(1) <br> (FPT-28P-M03) |  |

## PACKAGE DIMENSIONS

28-pin plastic SOP (FPT-28P-M17)

Note 1) *1: These dimensions include resin protrusion.
Note 2) *2 : These dimensions do not include resin protrusion.
Note 3) Pins width and pins thickness include plating thickness.
Note 4) Pins width do not include tie bar cutting remainder.

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Dimensions in mm (inches).
Note: The values in parentheses are reference values.
(Continued)
(Continued)
28-pin plastic TSOP(1)
(FPT-28P-M03)

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Dimensions in mm (inches).
Note: The values in parentheses are reference values.

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#### Abstract

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